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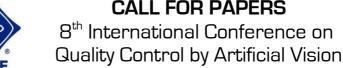
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QCAV'2007

Le Creusot, France, May 23-25, 2007 http://www.qcav.org



Scope. The objective of the QCAV'2007 conference is to provide a forum for researchers, industry, and users of vision systems to present and discuss the state-of-the-art in machine vision and image processing techniques, with an emphasis on industrial applications for quality control of manufactured products. The presentations will include contributed papers, poster sessions and invited speakers for state-of the-art talks in specialized subjects related to the conference topics. Papers describing original work concerning the theoretical and experimental aspects of image processing are invited. The Scientific Committee invites authors to submit original unpublished paper proposals which present industrial quality control applications. For the first time, a special video session will be organized. Authors are encouraged to submit to this video track.

THE PROCEEDINGS VOLUME WILL BE PUBLISHED BY SPIE AND BE AVAILABLE ONSITE.

A SELECTION OF THE BEST PAPERS WILL BE PUBLISHED IN A SPECIAL ISSUE OF THE JOURNAL OF ELECTRONIC IMAGING (CO-EDITED BY SPIE AND IS&T).

A SELECTION OF THE BEST PAPERS SUBMITTED TO THE VIDEO SESSION WILL BE PUBLISHED IN A SPECIAL ISSUE OF THE ELECTRONIC LETTERS ON COMPUTER VISION AND IMAGE ANALYSIS (EDITED BY CVC PRESS).

Topics & methods. Papers are invited that describe novel theoretical, experimental, and applied work in image processing and computer vision for industrial quality control through improved metrology, inspection, and process characterization. Papers are solicited from, but not limited to, the following categories:

- Vision Sensor Development and Integration
- Optical, Electron, X-ray, Ultrasound and other Imaging Modalities
- Non-destructive Testing and Metrology
- Image Processing, Transforms, Segmentation and Pattern Recognition
- Image Data Management, Analysis and Interpretation
- Process Automation, Characterization and Control
- Remote Diagnostics

There are many industries that are benefiting from artificial vision today. Papers are particularly encouraged from, but not limited to, the following industries:

Agriculture Metal Casting Mining **Aluminium** Biomedical Petroleum Chemicals Pharmaceuticals Food Semiconductors

Forest Products Steel Glass **Textiles**

Submission procedure. Prospective authors must submit an extended summary of approximately 2,000 words (not including references) in English. Summaries must be single column and formatted to fit 8.5 in. x 11 in. page size (or A4 format). Electronic submissions must be in Adobe PDF format only. Authors can choose either oral, poster or video presentation.

Video session. Video segments of between 5 to 15 minutes in length illustrating new and significant results are requested for the special video sessions. Videos must be accompanied by an extended abstract and should be submitted following the instructions on the web.

IMPORTANT DATES

Summary submission deadline Notification of acceptance Final manuscript due date Conference dates

November 9, 2006 December 14, 2006 February 2, 2007 May 23-25, 2007